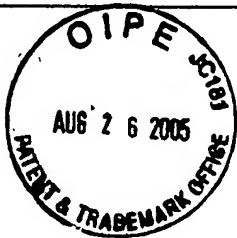


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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE	
<b>SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT</b>	Atty. Docket No. <b>UBAT1490-1</b>



Applicant(s) <b>Gregory R. Hanson et al.</b>	
Application Number <b>10/607,824</b>	Date Filed <b>June 27, 2003</b>
For <b>RECORDING MULTIPLE SPATIALLY- HETERODYNED DIRECT-TO-DIGITAL HOLOGRAMS IN ONE DIGITAL IMAGE</b>	
Group Art Unit <b>2621</b>	Examiner
Confirmation Number: <b>8424</b>	

Mail Stop Amendment  
Commissioner for Patents  
PO Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

<p align="center"><b><u>Certificate of Mailing Under 37 C.F.R. 1.8</u></b></p> <p>I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313 on <u>Aug 24</u>, 2005.</p> <p align="center"> John J. Bruckner</p>
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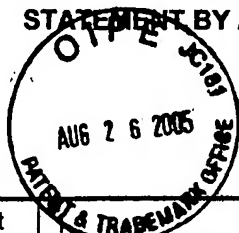
Applicant respectfully requests, pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, that the reference(s) listed on the attached PTO/SB/08A and/or PTO/SB/08B forms be considered and cited in the examination of the above-identified application. Pursuant to 37 C.F.R. §§ 1.97(g) and (h), no representation is made that a search has been made or that this art is material to the patentability of the present application. Copies of the non-US patent references are enclosed for the convenience of the Examiner.

While Applicants believe no (further) fees are due, if any (further) fees are due, the Commissioner is hereby authorized to charge any fees or credit any overpayments to Deposit Account No. 50-3204 of John Bruckner PC.

Dated: Aug 24, 2005

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Respectfully submitted,  
  
Attorneys for Applicant  
John J. Bruckner  
Reg. No. 35,816

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> 				Application Number		<b>10/607,824</b>	
				Filing Date		<b>June 27, 2003</b>	
				First Named Inventor		<b>Gregory R. Hanson</b>	
				Group Art Unit		<b>2621</b>	
				Examiner Name			
Sheet		of 1		Attorney Docket		<b>UBAT1490-1</b>	
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initials	Cite No.	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		
		Number	Kind Code (if known)				
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		Country Code	Number	Kind Code (if known)			
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Examiner Signature					Date Considered		

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				Group Art Unit	2621	
				Examiner Name		
Sheet	1	of	2	Attorney Docket Number	UBAT1490-1	
<b>NON-PATENT LITERATURE DOCUMENTS</b>						
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Examiner Signature					Date Considered	

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Sheet	2	of	2	Attorney Docket Number	UBAT1490-1	
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